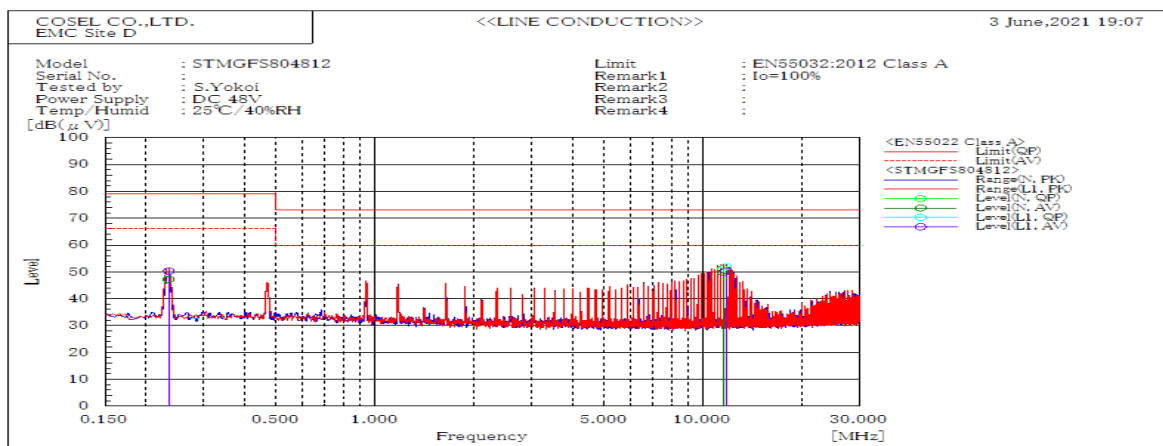
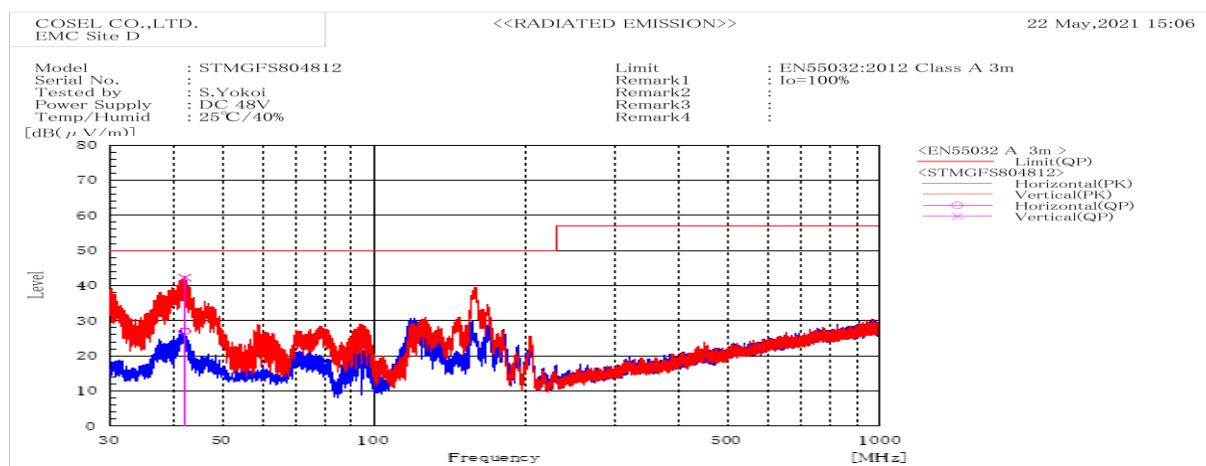


DATA SHEET		Date	08-Jul-21
Model	STMGFS804812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Yokoi



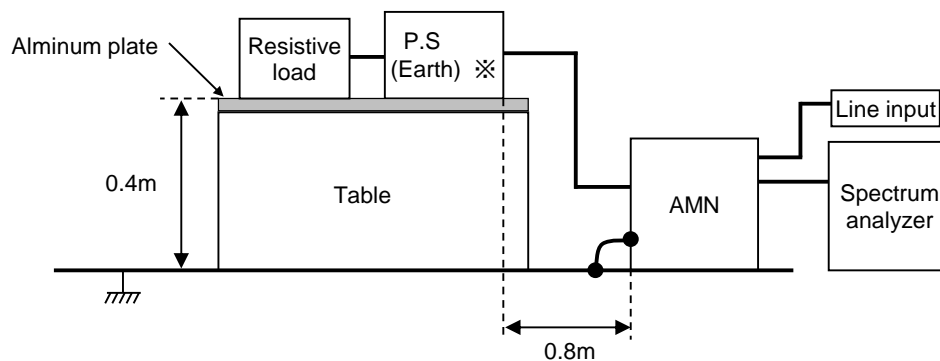
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.235	L1	50.4	50.2	79	66	28.6	15.8	Pass	
11.742	L1	51.9	50.4	73	60	21.1	9.6	Pass	
0.235	N	47.3	47.2	79	66	31.7	18.8	Pass	
11.504	N	51.2	49.8	73	60	21.8	10.2	Pass	



Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB				
			QP	QP	QP				
42.126	V	Stable	42.3	50	7.7	Pass	100.2	350	
42.118	H	Stable	27	50	23	Pass	200	32.5	

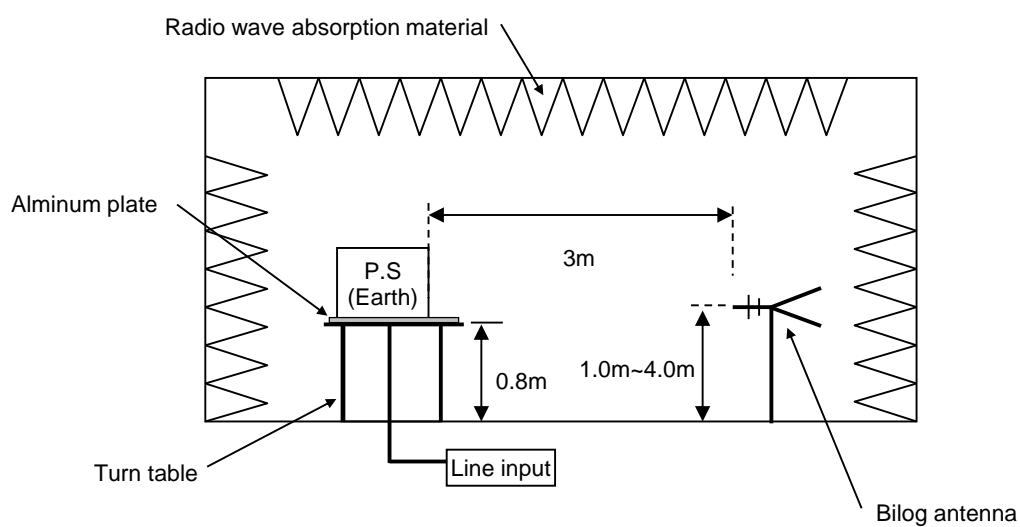
DATA SHEET		Date	08-Jul-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Yokoi

1. Line conduction



※External capacitor on the input side : 120 μ F

2. Radiated emission



Conditions

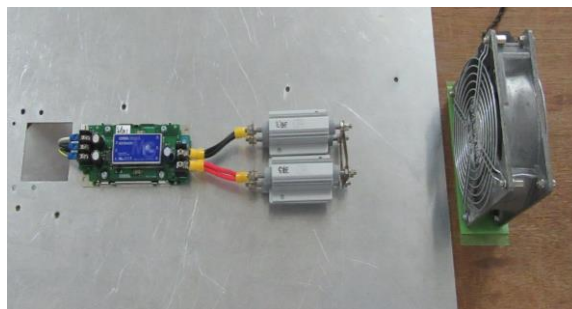
Test : EMI

Model Name : STMGFS80□□

○Photographs of Test Set-Up
LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

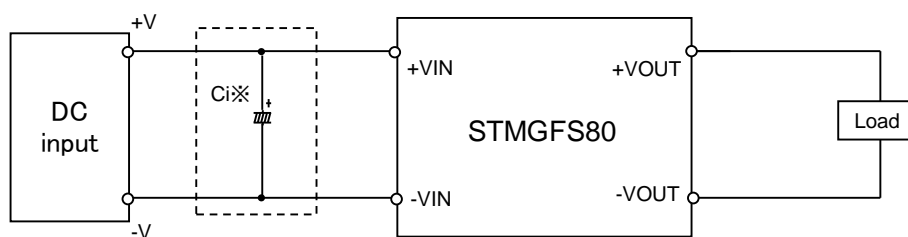


Fig.1 Testing circuitry

※Ci : External capacitor on the input side when LINE CONDUCTION

Ci : STMGFS8024□□ 220 μ F
STMGFS8048□□ 120 μ F